

41st RD50 Workshop on Radiation Hard Semiconductor Devices for Very High Luminosity Colliders (Sevilla, Spain)



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Update on the characterization of neutron irradiated IMB-CNM SiC planar diodes

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A radiation tolerance study of planar diodes fabricated on a SiC substrate will be presented. TPA-TCT and TRIBIC methods were used to characterize the samples. The measurement campaign was carried out at the laser facility of the EHU-UPV university and the CNA microbeam.

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